
Kristalni oscilatorji določene kakovosti - 6. del: Metoda za merjenje faznega trepetanja kristalnih oscilatorjev in oscilatorjev SAW - Navodilo za uporabo (IEC 60679-6:2011)

Quartz crystal controlled oscillators of assessed quality - Part 6: Phase jitter measurement method for quartz crystal oscillators and SAW oscillators - Application guidelines (IEC 60679-6:2011)

Quarzoszillatoren mit bewerteter Qualität - Teil 6: Phasenjitter-Messverfahren für Quarzoszillatoren und OFW-Oszillatoren - Leitfaden für die Anwendung (IEC 60679-6:2011)

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Oscillateurs pilotés par quartz sous assurance de la qualité - Partie 6: Méthode de mesure de la gigue de phase pour les oscillateurs à quartz et les oscillateurs SAW - Lignes directrices pour l'application (CEI 60679-6:2011)

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**Quartz crystal controlled oscillators of assessed quality -
Part 6: Phase jitter measurement method for quartz crystal oscillators and
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Application guidelines
(IEC 60679-6:2011)**

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European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

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Foreword

The text of document 49/935/FDIS, future edition 1 of IEC 60679-6, prepared by IEC TC 49, Piezoelectric, Dielectric and Electrostatic Devices and Associated Materials for Frequency Control, Selection and Detection, was submitted to the IEC-CENELEC parallel vote and was approved by CENELEC as EN 60679-6 on 2011-04-18.

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The following dates were fixed:

- latest date by which the EN has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2012-01-18
- latest date by which the national standards conflicting with the EN have to be withdrawn (dow) 2014-04-18

Annex ZA has been added by CENELEC.

Endorsement notice

The text of the International Standard IEC 60679-6:2011 was approved by CENELEC as a European Standard without any modification. (standards.iteh.ai)

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Annex ZA (normative)

Normative references to international publications with their corresponding European publications

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE When an international publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60679-1	2007	Quartz crystal controlled oscillators of assessed quality - Part 1: Generic specification	EN 60679-1	2007

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Part 6: Phase jitter measurement method for quartz crystal oscillators and SAW
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INTERNATIONAL ELECTROTECHNICAL COMMISSION

**QUARTZ CRYSTAL CONTROLLED OSCILLATORS
OF ASSESSED QUALITY –****Part 6: Phase jitter measurement method
for quartz crystal oscillators and SAW oscillators –
Application guidelines**

FOREWORD

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International Standard IEC 60679-6 has been prepared by IEC technical committee 49: Piezoelectric, dielectric and electrostatic devices and associated materials for frequency control, selection and detection.

This standard cancels and replaces IEC/PAS 60679-6 published in 2008. This first edition constitutes a technical revision.

The text of this standard is based on the following documents:

FDIS	Report on voting
49/935/FDIS	49/944/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts of the IEC 60679 series, published under the general title *Quartz crystal controlled oscillators of assessed quality*, can be found on the IEC website.

The committee has decided that the contents of this publication will remain unchanged until the stability date indicated on the IEC web site under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

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